Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/643,669	TANNER ET AL.	
Examiner	Art Unit	
John Kim	1723	

	SEARCHED				
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Inventor Search	3/1/2006	ΥK
See EAST Search History 210/501,502.1,504,505,506,508,266,2 82,497.1,473,477,252,257.1,257.2,25 9	3/3/2006	YK
EAST Search History	8/23/2006	JK
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